



Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from,Europe,America and south Asia,supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of “Quality Parts,Customers Priority,Honest Operation,and Considerate Service”,our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip,ALPS,ROHM,Xilinx,Pulse,ON,Everlight and Freescale. Main products comprise IC,Modules,Potentiometer,IC Socket,Relay,Connector.Our parts cover such applications as commercial,industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



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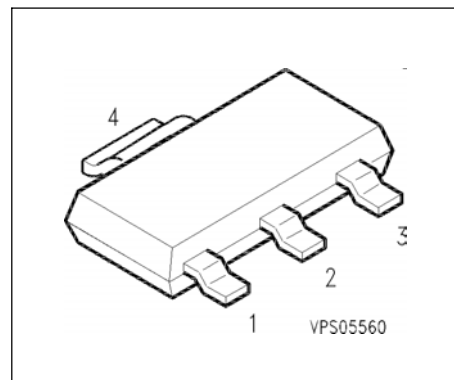
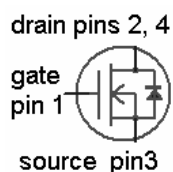
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SIPMOS® Small-Signal Transistor

- N channel
 - Enhancement mode
 - Avalanche rated
 - $V_{GS(th)} = 2.1 \dots 4.0 \text{ V}$
 - Pb-free lead plating; RoHS compliant
 - Qualified according to AEC Q101
- øHalogen-free according to IEC 61249-2-21



Pin 1	Pin 2	Pin 3	Pin 4
G	D	S	D



Type	V_{DS}	I_D	$R_{DS(on)}$	Package	Marking
BSP 299	500 V	0.4 A	4 Ω	SOT-223	BSP299

Type	Pb-free	Tape and Reel Information	Packaging
BSP 299	Yes	H6327: 1000 pcs / reel	Dry

Maximum Ratings

Parameter	Symbol	Values	Unit
Continuous drain current $T_A = 25 \text{ }^\circ\text{C}$	I_D	0.4	A
DC drain current, pulsed $T_A = 25 \text{ }^\circ\text{C}$	I_{Dpuls}	1.6	
Avalanche energy, single pulse $I_D = 1.2 \text{ A}$, $R_{GS} = 25 \text{ } \Omega$ $T_j = 25 \text{ }^\circ\text{C}$	E_{AS}	130	mJ
Gate source voltage	V_{GS}	± 20	V
Power dissipation $T_A = 25 \text{ }^\circ\text{C}$	P_{tot}	1.8	W
ESD Class JESD22-A114-HBM		Class 1b	

Maximum Ratings

Parameter	Symbol	Values	Unit
Chip or operating temperature	T_j	-55 ... + 150	°C
Storage temperature	T_{stg}	-55 ... + 150	
Thermal resistance, chip to ambient air ¹⁾	R_{thJA}	≤ 70	K/W
Thermal resistance, junction-soldering point	R_{thJS}	≤ 25	
DIN humidity category, DIN 40 040		E	
IEC climatic category, DIN IEC 68-1		55 / 150 / 56	

1) Transistor on epoxy pcb 40 mm x 40 mm x 1,5 mm with 6 cm² copper area for drain connection

Electrical Characteristics, at $T_j = 25^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	

Static Characteristics

Drain- source breakdown voltage $V_{GS} = 0 \text{ V}, I_D = 0.25 \text{ mA}, T_j = 0^\circ\text{C}$	$V_{(BR)DSS}$	500	-	-	V
Gate threshold voltage $V_{GS}=V_{DS}, I_D = 1 \text{ mA}$	$V_{GS(th)}$	2.1	3	4	
Zero gate voltage drain current $V_{DS} = 500 \text{ V}, V_{GS} = 0 \text{ V}, T_j = 25^\circ\text{C}$ $V_{DS} = 500 \text{ V}, V_{GS} = 0 \text{ V}, T_j = 125^\circ\text{C}$	I_{DSS}	-	0.1 10	1 100	μA
Gate-source leakage current $V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$	I_{GSS}	-	10	100	
Drain-Source on-state resistance $V_{GS} = 10 \text{ V}, I_D = 0.4 \text{ A}$	$R_{DS(on)}$	-	3.1	4	Ω

Electrical Characteristics, at $T_j = 25^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	

Dynamic Characteristics

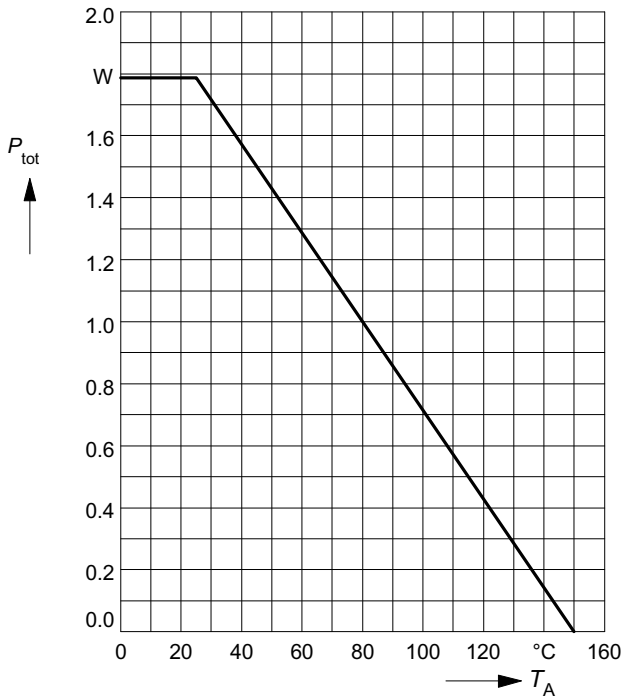
Transconductance $V_{DS} \geq 2 \cdot I_D \cdot R_{DS(on)max}, I_D = 0.4 \text{ A}$	g_{fs}	0.3	1.2	-	S
Input capacitance $V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	C_{iss}	-	300	400	pF
Output capacitance $V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	C_{oss}	-	40	60	
Reverse transfer capacitance $V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	C_{rss}	-	15	25	
Turn-on delay time $V_{DD} = 30 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 0.3 \text{ A}$ $R_{GS} = 50 \Omega$	$t_{d(on)}$	-	8	12	ns
Rise time $V_{DD} = 30 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 0.3 \text{ A}$ $R_{GS} = 50 \Omega$	t_r	-	15	22	
Turn-off delay time $V_{DD} = 30 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 0.3 \text{ A}$ $R_{GS} = 50 \Omega$	$t_{d(off)}$	-	55	70	
Fall time $V_{DD} = 30 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 0.3 \text{ A}$ $R_{GS} = 50 \Omega$	t_f	-	30	40	

Electrical Characteristics, at $T_j = 25^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Reverse Diode					
Inverse diode continuous forward current $T_A = 25^\circ\text{C}$	I_S	-	-	0.4	A
Inverse diode direct current, pulsed $T_A = 25^\circ\text{C}$	I_{SM}	-	-	1.6	
Inverse diode forward voltage $V_{GS} = 0\text{ V}$, $I_F = 0.8\text{ A}$, $T_j = 25^\circ\text{C}$	V_{SD}	-	0.9	1.2	V
Reverse recovery time $V_R = 100\text{ V}$, $I_F = I_S$, $di_F/dt = 100\text{ A}/\mu\text{s}$	t_{rr}	-	300	-	ns
Reverse recovery charge $V_R = 100\text{ V}$, $I_F = I_S$, $di_F/dt = 100\text{ A}/\mu\text{s}$	Q_{rr}	-	2.5	-	μC

Power dissipation

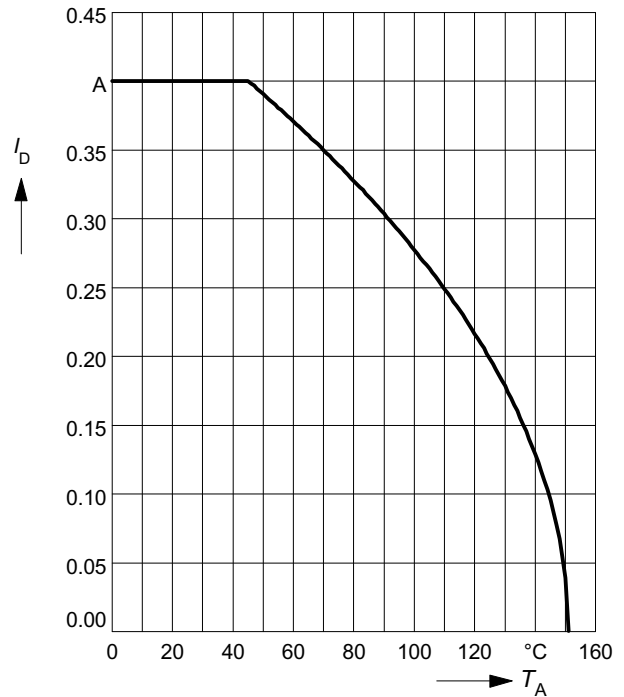
$$P_{tot} = f(T_A)$$



Drain current

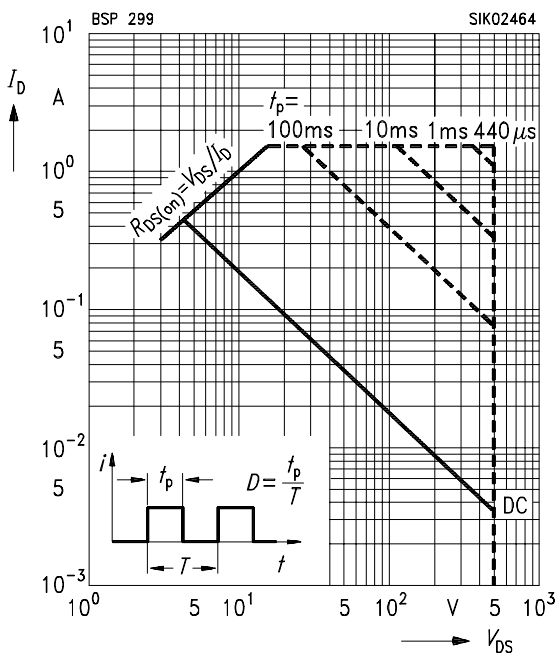
$$I_D = f(T_A)$$

parameter: $V_{GS} \geq 10 \text{ V}$



Safe operating area $I_D = f(V_{DS})$

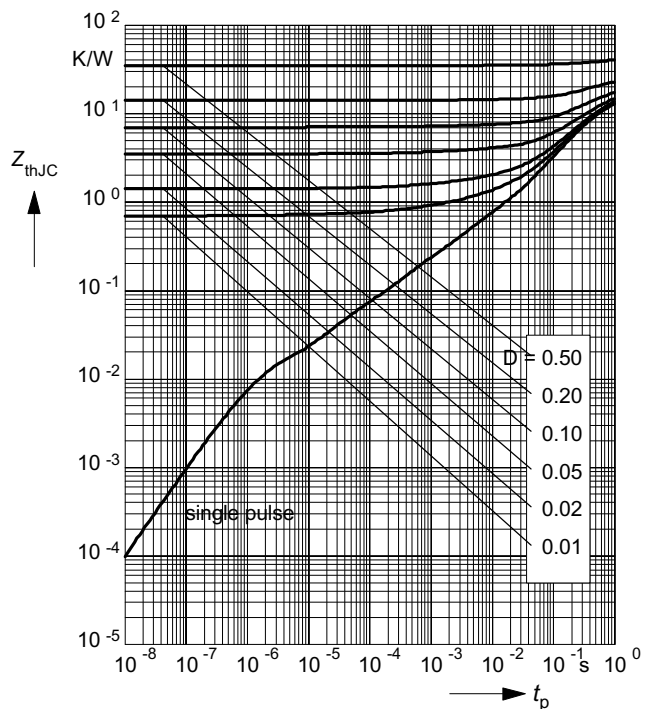
parameter : $D = 0, T_C = 25^\circ\text{C}$



Transient thermal impedance

$$Z_{th\text{JA}} = f(t_p)$$

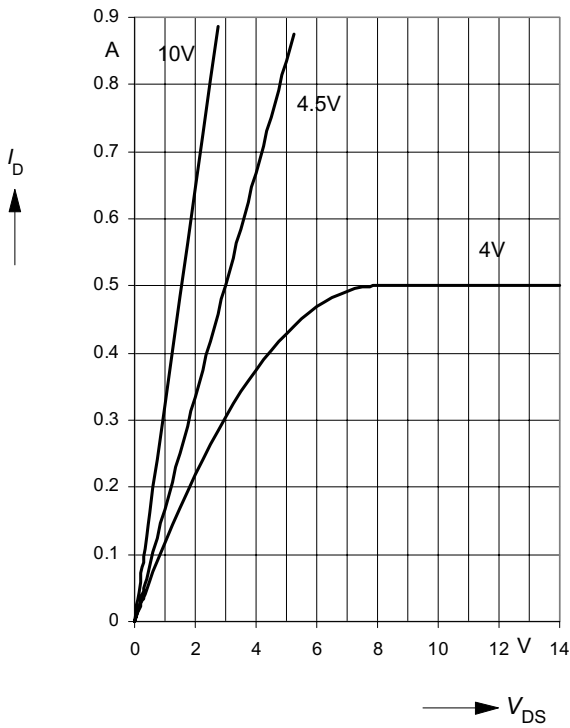
parameter: $D = t_p / T$



Typ. output characteristics

$I_D = f(V_{DS})$

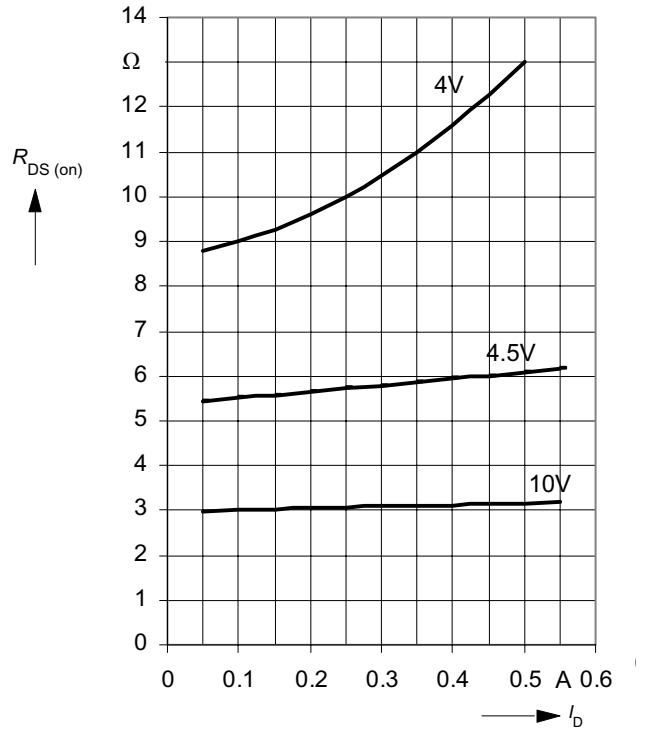
parameter: V_{GS} , $T_j = 25\text{ °C}$



Typ. drain-source on-resistance

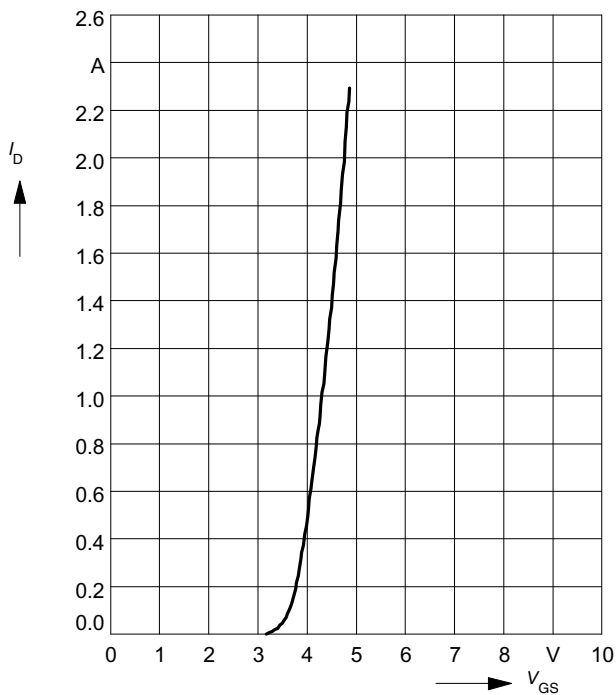
$R_{DS(on)} = f(I_D)$

parameter: V_{GS} , $T_j = 25\text{ °C}$



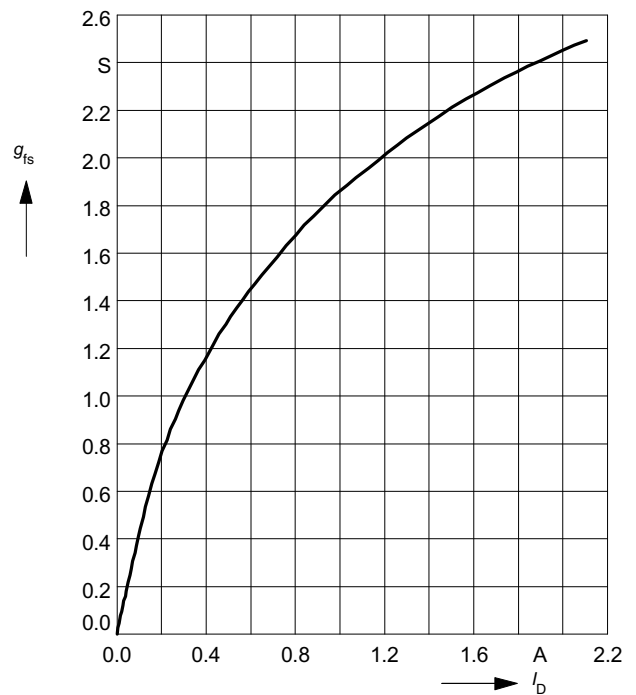
Typ. transfer characteristics $I_D = f(V_{GS})$

parameter: $t_p = 80\text{ μs}$



Typ. forward transconductance $g_{fs} = f(I_D)$

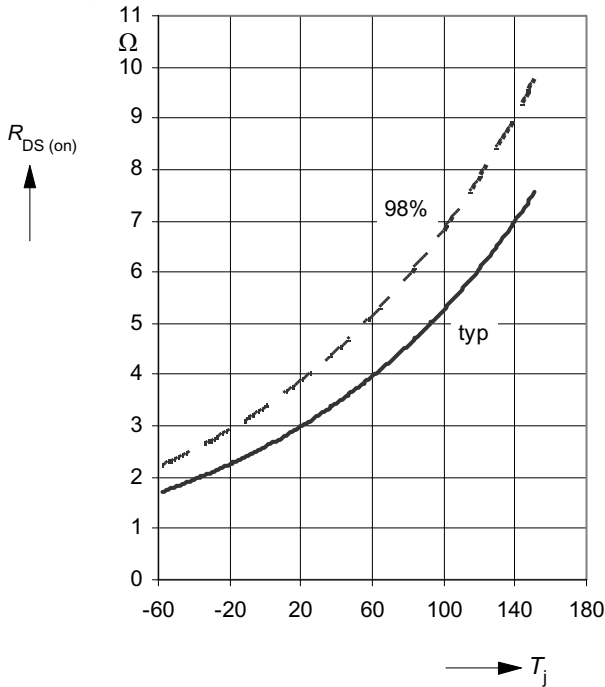
parameter: $t_p = 80\text{ μs}$,



Drain-source on-resistance

$$R_{DS(on)} = f(T_j)$$

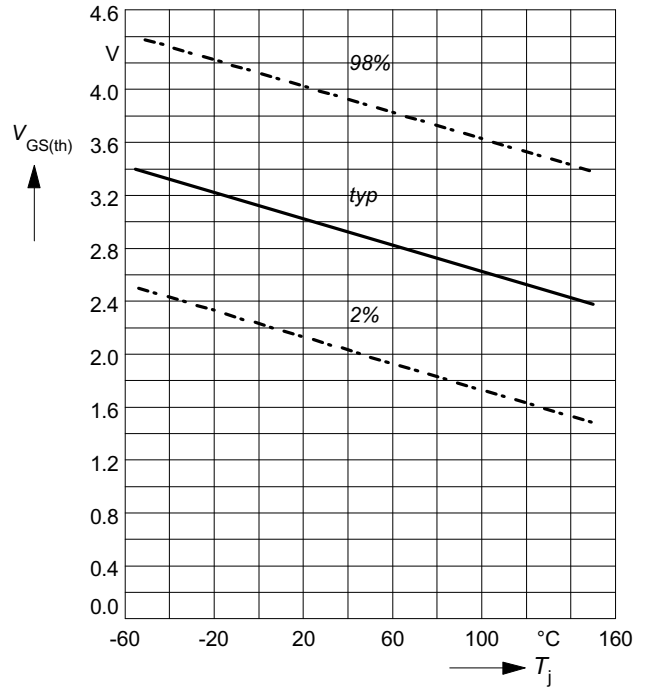
parameter: $I_D = 0.4 \text{ A}$, $V_{GS} = 10 \text{ V}$



Gate threshold voltage

$$V_{GS(th)} = f(T_j)$$

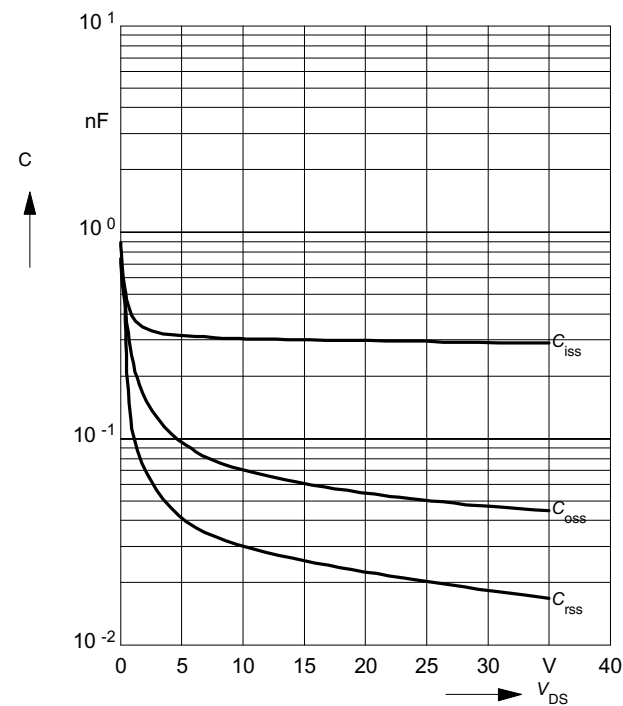
parameter: $V_{GS} = V_{DS}$, $I_D = 1 \text{ mA}$



Typ. capacitances

$$C = f(V_{DS})$$

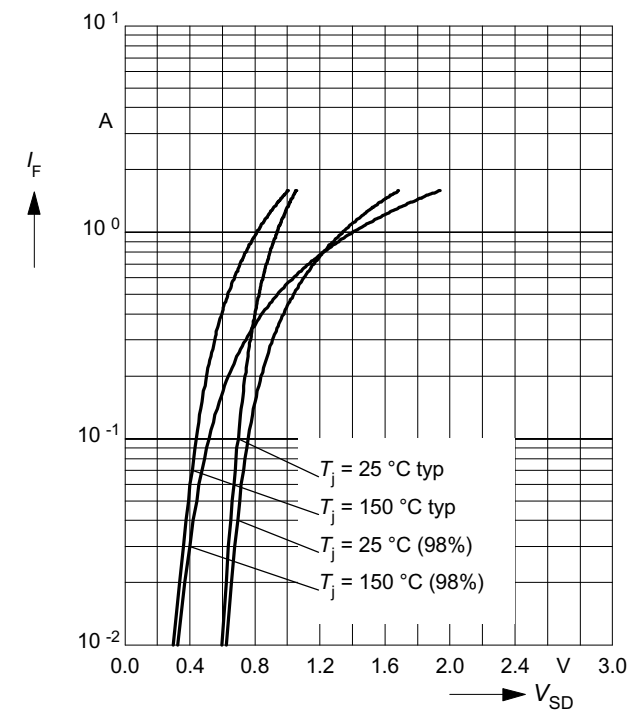
parameter: $V_{GS}=0\text{V}$, $f = 1 \text{ MHz}$



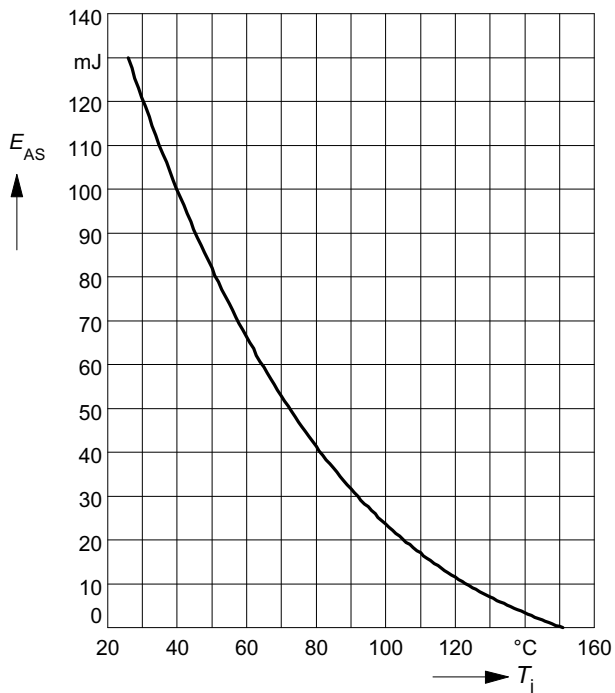
Forward characteristics of reverse diode

$$I_F = f(V_{SD})$$

parameter: $T_j, t_p = 80 \mu\text{s}$

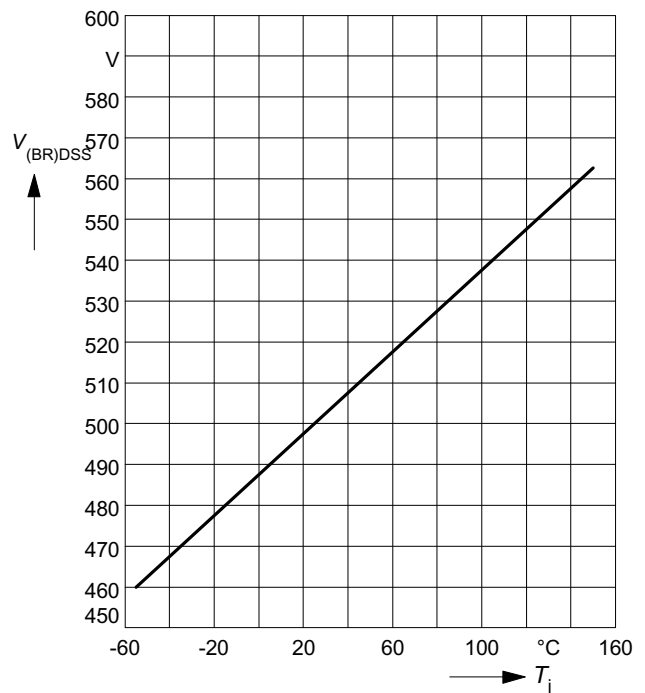


Avalanche energy $E_{AS} = f(T_j)$
 parameter: $I_D = 1.2 \text{ A}$, $V_{DD} = 50 \text{ V}$
 $R_{GS} = 25 \Omega$, $L = 163 \text{ mH}$



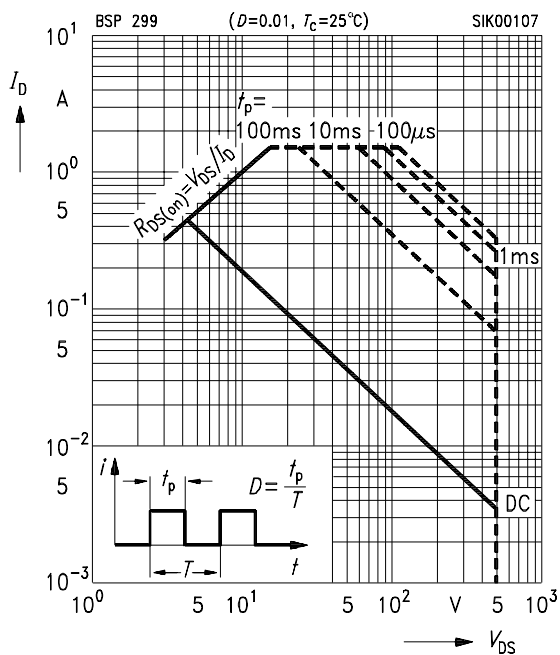
Drain-source breakdown voltage

$V_{(BR)DSS} = f(T_j)$



Safe operating area $I_D = f(V_{DS})$

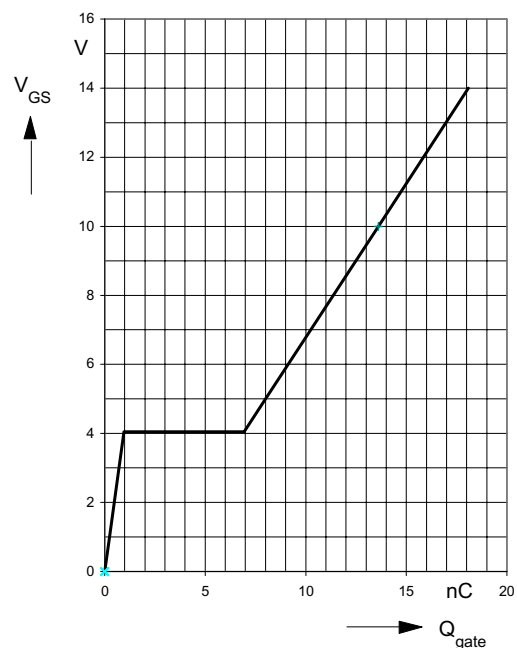
parameter : $D = 0.01$, $T_C = 25^\circ\text{C}$



Typ. gate charge

$V_{GS} = f(Q_{gate})$; $I_D = 0.4 \text{ A}$ pulsed

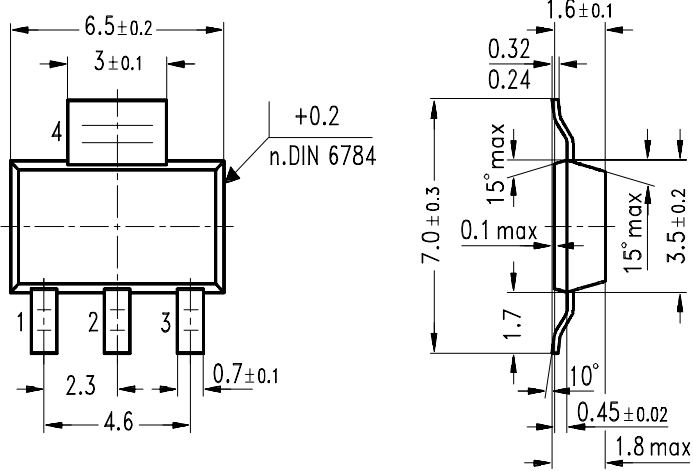
$V_{DD} = 200 \text{ V}$



Package outlines

SOT-223

Dimensions in mm



GPS05560

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